

## **Search Notes**



**Application/Control No.**

10/522,772

Examiner

David Y. Chung

**Applicant(s)/Patent under  
Reexamination**

FUNAHATA ET AL.

## **Art Unit**

2871

**SEARCHED**

## **INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
<b>same</b>	<b>same</b>	5/29/2007	<b>DC</b>

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**